

**Search Notes**

Application/Control No.

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Examiner

Leith A. Al-Nazer

Applicant(s)/Patent under  
Reexamination

ONOZAWA ET AL.

Art Unit

2821

**SEARCHED**

Class	Subclass	Date	Examiner
315	169.3, 169.4	7/22/2005	LA
345	55, 60	7/22/2005	LA
345	204	7/22/2005	LA
327	111, 333	7/22/2005	LA

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text search (see "Examiner Search Notes")	7/22/2005	LA